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Diagnosis in Analog Electronic Circuits, Electrical Power Systems and Smart Grids

Guest Editors:

Prof. Dr. Maria Cristina Piccirilli

Department of Information Engineering, University of Florence, Florence, Italy

Prof. Dr. Antonio Luchetta

Department of Information Engineering, University of Florence, Florence, Italy

Deadline for manuscript submissions:

closed (30 March 2022)

Message from the Guest Editors

Dear Colleagues,

This Special Issue will promote advancement in the following topics related to the diagnosis of analog electronic circuits, electrical power systems, and smart grids:

- Parametric fault diagnosis in analog circuits;
- Catastrophic fault diagnosis in analog circuits;
- Testability, solvability, and ambiguity group determination in lumped circuits;
- Smart metering and soft computing techniques applied to the fault diagnosis;
- Diagnosis and prognosis techniques in electrical power systems;
- Smart grids: maintenance, fault prevention, fault resolution, fault-tolerant approach;
- Smart grids: non-intrusive monitoring techniques;
- CAD and simulation techniques oriented to analog circuits fault diagnosis

We welcome your contribution.











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Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

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